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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I ² C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 19x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f078rbt6

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2 Description

The STM32F078CB/RB/VB microcontrollers incorporate the high-performance ARM® Cortex®-M0 32-bit RISC core operating at up to 48 MHz frequency, high-speed embedded memories (128 Kbytes of Flash memory and 16 Kbytes of SRAM), and an extensive range of enhanced peripherals and I/Os. All devices offer standard communication interfaces (two I²Cs, two SPI/I²S, one HDMI CEC and four USARTs), one USB Full-speed device (crystal-less), one 12-bit ADC, one 12-bit DAC with two channels, seven 16-bit timers, one 32-bit timer and an advanced-control PWM timer.

The STM32F078CB/RB/VB microcontrollers operate in the -40 to +85 °C and -40 to +105 °C temperature ranges from a 1.8 V ± 8% power supply. A comprehensive set of power-saving modes allows the design of low-power applications.

The STM32F078CB/RB/VB microcontrollers include devices in six different packages ranging from 48 pins to 100 pins with a die form also available upon request. Depending on the device chosen, different sets of peripherals are included.

These features make the STM32F078CB/RB/VB microcontrollers suitable for a wide range of applications such as application control and user interfaces, hand-held equipment, A/V receivers and digital TV, PC peripherals, gaming and GPS platforms, industrial applications, PLCs, inverters, printers, scanners, alarm systems, video intercoms and HVACs.

sensor, voltage reference, VBAT voltage measurement) channels and performs conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Table 2. Temperature sensor calibration values

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C (± 5 °C), $V_{\text{DDA}} = 3.3$ V (± 10 mV)	0x1FFF F7B8 - 0x1FFF F7B9
TS_CAL2	TS ADC raw data acquired at a temperature of 110 °C (± 5 °C), $V_{\text{DDA}} = 3.3$ V (± 10 mV)	0x1FFF F7C2 - 0x1FFF F7C3

3.10.2 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC and comparators. V_{REFINT} is internally connected to the ADC_IN17 input channel. The precise voltage of V_{REFINT} is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

Table 3. Internal voltage reference calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at a temperature of 30 °C (± 5 °C), $V_{\text{DDA}} = 3.3$ V (± 10 mV)	0x1FFF F7BA - 0x1FFF F7BB

The RTC is an independent BCD timer/counter. Its main features are the following:

- calendar with subseconds, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format
- automatic correction for 28, 29 (leap year), 30, and 31 day of the month
- programmable alarm with wake up from Stop mode capability
- Periodic wakeup unit with programmable resolution and period.
- on-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize the RTC with a master clock
- digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy
- Three anti-tamper detection pins with programmable filter. The MCU can be woken up from Stop mode on tamper event detection
- timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be woken up from Stop mode on timestamp event detection
- reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision

The RTC clock sources can be:

- a 32.768 kHz external crystal
- a resonator or oscillator
- the internal low-power RC oscillator (typical frequency of 40 kHz)
- the high-speed external clock divided by 32

3.16 Inter-integrated circuit interface (I²C)

Up to two I²C interfaces (I2C1 and I2C2) can operate in multimaster or slave modes. Both can support Standard mode (up to 100 kbit/s), Fast mode (up to 400 kbit/s) and Fast Mode Plus (up to 1 Mbit/s) with extra output drive on most of the associated I/Os.

Both support 7-bit and 10-bit addressing modes, multiple 7-bit slave addresses (two addresses, one with configurable mask). They also include programmable analog and digital noise filters.

Table 7. Comparison of I²C analog and digital filters

Aspect	Analog filter	Digital filter
Pulse width of suppressed spikes	≥ 50 ns	Programmable length from 1 to 15 I2Cx peripheral clocks
Benefits	Available in Stop mode	–Extra filtering capability vs. standard requirements –Stable length
Drawbacks	Variations depending on temperature, voltage, process	Wakeup from Stop on address match is not available when digital filter is enabled.

In addition, I2C1 provides hardware support for SMBUS 2.0 and PMBUS 1.1: ARP capability, Host notify protocol, hardware CRC (PEC) generation/verification, timeouts

Table 9. STM32F078CB/RB/VB USART implementation (continued)

USART modes/features ⁽¹⁾	USART1 and USART2	USART3 and USART4
IrDA SIR ENDEC block	X	-
LIN mode	X	-
Dual clock domain and wakeup from Stop mode	X	-
Receiver timeout interrupt	X	-
Modbus communication	X	-
Auto baud rate detection	X	-
Driver Enable	X	X

1. X = supported.

3.18 Serial peripheral interface (SPI) / Inter-integrated sound interface (I²S)

Two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

Two standard I²S interfaces (multiplexed with SPI1 and SPI2 respectively) supporting four different audio standards can operate as master or slave at half-duplex communication mode. They can be configured to transfer 16 and 24 or 32 bits with 16-bit or 32-bit data resolution and synchronized by a specific signal. Audio sampling frequency from 8 kHz up to 192 kHz can be set by an 8-bit programmable linear prescaler. When operating in master mode, they can output a clock for an external audio component at 256 times the sampling frequency.

Table 10. STM32F078CB/RB/VB SPI/I²S implementation

SPI features ⁽¹⁾	SPI1 and SPI2
Hardware CRC calculation	X
Rx/Tx FIFO	X
NSS pulse mode	X
I ² S mode	X
TI mode	X

1. X = supported.

3.19 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The device embeds a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory

6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 20: Voltage characteristics](#), [Table 21: Current characteristics](#) and [Table 22: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 20. Voltage characteristics⁽¹⁾

Symbol	Ratings	Min	Max	Unit
$V_{DD}-V_{SS}$	External main supply voltage	-0.3	1.95	V
$V_{DDIO2}-V_{SS}$	External I/O supply voltage	- 0.3	4.0	V
$V_{DDA}-V_{SS}$	External analog supply voltage	- 0.3	4.0	V
$V_{DD}-V_{DDA}$	Allowed voltage difference for $V_{DD} > V_{DDA}$	-	0.4	V
$V_{BAT}-V_{SS}$	External backup supply voltage	- 0.3	4.0	V
$V_{IN}^{(2)}$	Input voltage on FT and FTf pins	$V_{SS} - 0.3$	$V_{DDIOx} + 4.0^{(3)}$	V
	Input voltage on POR pins	$V_{SS} - 0.3$	4.0	V
	Input voltage on TTa pins	$V_{SS} - 0.3$	4.0	V
	BOOT0	0	9.0	V
	Input voltage on any other pin	$V_{SS} - 0.3$	4.0	V
$ \Delta V_{DDx} $	Variations between different V_{DD} power pins	-	50	mV
$ V_{SSx} - V_{SS} $	Variations between all the different ground pins	-	50	mV
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see Section 6.3.11: Electrical sensitivity characteristics		-

1. All main power (V_{DD} , V_{DDA}) and ground (V_{SS} , V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum must always be respected. Refer to [Table 21: Current characteristics](#) for the maximum allowed injected current values.
3. Valid only if the internal pull-up/pull-down resistors are disabled. If internal pull-up or pull-down resistor is enabled, the maximum limit is 4 V.

Table 21. Current characteristics

Symbol	Ratings	Max.	Unit
ΣI_{VDD}	Total current into sum of all VDD power lines (source) ⁽¹⁾	120	mA
ΣI_{VSS}	Total current out of sum of all VSS ground lines (sink) ⁽¹⁾	-120	
$I_{VDD(PIN)}$	Maximum current into each VDD power pin (source) ⁽¹⁾	100	
$I_{VSS(PIN)}$	Maximum current out of each VSS ground pin (sink) ⁽¹⁾	-100	
$I_{IO(PIN)}$	Output current sunk by any I/O and control pin	25	
	Output current source by any I/O and control pin	-25	
$\Sigma I_{IO(PIN)}$	Total output current sunk by sum of all I/Os and control pins ⁽²⁾	80	
	Total output current sourced by sum of all I/Os and control pins ⁽²⁾	-80	
	Total output current sourced by sum of all I/Os supplied by VDDIO2	-40	
$I_{INJ(PIN)}^{(3)}$	Injected current on POR, B, FT and FTf pins	-5/+0 ⁽⁴⁾	
	Injected current on TC and RST pin	± 5	
	Injected current on TTa pins ⁽⁵⁾	± 5	
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/O and control pins) ⁽⁶⁾	± 25	

1. All main power (VDD, VDDA) and ground (VSS, VSSA) pins must always be connected to the external power supply, in the permitted range.
2. This current consumption must be correctly distributed over all I/Os and control pins. The total output current must not be sunk/sourced between two consecutive power supply pins referring to high pin count QFP packages.
3. A positive injection is induced by $V_{IN} > V_{DDIOx}$ while a negative injection is induced by $V_{IN} < V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to [Table 20: Voltage characteristics](#) for the maximum allowed input voltage values.
4. Positive injection is not possible on these I/Os and does not occur for input voltages lower than the specified maximum value.
5. On these I/Os, a positive injection is induced by $V_{IN} > V_{DDA}$. Negative injection disturbs the analog performance of the device. See note ⁽²⁾ below [Table 57: ADC accuracy](#).
6. When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values).

Table 22. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	-65 to +150	°C
T_J	Maximum junction temperature	150	°C

Typical current consumption

The MCU is placed under the following conditions:

- $V_{DD} = V_{DDA} = 1.8\text{ V}$
- All I/O pins are in analog input configuration
- The Flash memory access time is adjusted to f_{HCLK} frequency:
 - 0 wait state and Prefetch OFF from 0 to 24 MHz
 - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled, $f_{PCLK} = f_{HCLK}$
- PLL is used for frequencies greater than 8 MHz
- AHB prescaler of 2, 4, 8 and 16 is used for the frequencies 4 MHz, 2 MHz, 1 MHz and 500 kHz respectively

Table 29. Typical current consumption, code executing from Flash memory, running from HSE 8 MHz crystal

Symbol	Parameter	f _{HCLK}	Typical consumption in Run mode		Typical consumption in Sleep mode		Unit
			Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	
I _{DD}	Current consumption from V _{DD} supply	48 MHz	22.0	12.7	14.2	3.2	mA
		36 MHz	17.1	9.9	10.8	2.5	
		32 MHz	15.4	8.9	9.7	2.2	
		24 MHz	11.9	7.0	7.5	1.8	
		16 MHz	8.3	4.9	5.2	1.3	
		8 MHz	4.4	2.7	2.7	0.7	
		4 MHz	2.7	1.7	1.8	0.6	
		2 MHz	1.6	1.1	1.2	0.6	
		1 MHz	1.1	0.8	0.9	0.5	
		500 kHz	0.9	0.7	0.8	0.5	
I _{DDA}	Current consumption from V _{DDA} supply	48 MHz	143				μA
		36 MHz	112				
		32 MHz	102				
		24 MHz	81				
		16 MHz	59				
		8 MHz	1				
		4 MHz	1				
		2 MHz	1				
		1 MHz	1				
		500 kHz	1				

Table 32. Peripheral current consumption (continued)

Peripheral		Typical consumption at 25 °C	Unit
APB	APB-Bridge ⁽²⁾	2.8	μA/MHz
	ADC ⁽³⁾	4.1	
	CEC	1.5	
	CRS	0.8	
	DAC ⁽³⁾	4.7	
	DEBUG (MCU debug feature)	0.1	
	I2C1	3.9	
	I2C2	4.0	
	PWR	1.3	
	SPI1	8.7	
	SPI2	8.5	
	SYSCFG & COMP	1.7	
	TIM1	14.9	
	TIM2	15.5	
	TIM3	11.4	
	TIM6	2.5	
	TIM7	2.3	
	TIM14	5.3	
	TIM15	9.1	
	TIM16	6.6	
	TIM17	6.8	
	USART1	17.0	
	USART2	16.7	
	USART3	5.4	
	USART4	5.4	
	USB	7.2	
	WWDG	1.4	
	All APB peripherals	169.6	

1. The BusMatrix is automatically active when at least one master is ON (CPU, DMA).
2. The APB Bridge is automatically active when at least one peripheral is ON on the Bus.
3. The power consumption of the analog part (I_{DDA}) of peripherals such as ADC, DAC, Comparators, is not included. Refer to the tables of characteristics in the subsequent sections.

6.3.5 Wakeup time from low-power mode

The wakeup times given in [Table 33](#) are the latency between the event and the execution of the first user instruction. The device goes in low-power mode after the WFE (Wait For Event) instruction, in the case of a WFI (Wait For Interruption) instruction, 16 CPU cycles must be added to the following timings due to the interrupt latency in the Cortex M0 architecture.

The SYSCLK clock source setting is kept unchanged after wakeup from Sleep mode. During wakeup from Stop mode, SYSCLK takes the default setting: HSI 8 MHz.

The wakeup source from Sleep and Stop mode is an EXTI line configured in event mode.

All timings are derived from tests performed under the ambient temperature and supply voltage conditions summarized in [Table 23: General operating conditions](#).

Table 33. Low-power mode wakeup timings

Symbol	Parameter	Typ @ V _{DDA}		Max	Unit
		= 1.8 V	= 3.3 V		
t _{WUSTOP}	Wakeup from Stop mode	3.5	2.8	5.3	μs
t _{WUSLEEP}	Wakeup from Sleep mode	4 SYSCLK cycles		-	μs

6.3.6 External clock source characteristics

High-speed external user clock generated from an external source

In bypass mode the HSE oscillator is switched off and the input pin is a standard GPIO.

The external clock signal has to respect the I/O characteristics in [Section 6.3.13](#). However, the recommended clock input waveform is shown in [Figure 14: High-speed external clock source AC timing diagram](#).

Table 34. High-speed external user clock characteristics

Symbol	Parameter ⁽¹⁾	Min	Typ	Max	Unit
f _{HSE_ext}	User external clock source frequency	-	8	32	MHz
V _{HSEH}	OSC_IN input pin high level voltage	0.7 V _{DDIOx}	-	V _{DDIOx}	V
V _{HSEL}	OSC_IN input pin low level voltage	V _{SS}	-	0.3 V _{DDIOx}	
t _{w(HSEH)} t _{w(HSEL)}	OSC_IN high or low time	15	-	-	ns
t _{r(HSE)} t _{f(HSE)}	OSC_IN rise or fall time	-	-	20	

1. Guaranteed by design, not tested in production.

Low-speed internal (LSI) RC oscillator

Table 41. LSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSI}	Frequency	30	40	50	kHz
$t_{su(LSI)}^{(2)}$	LSI oscillator startup time	-	-	85	μ s
$I_{DDA(LSI)}^{(2)}$	LSI oscillator power consumption	-	0.75	1.2	μ A

1. $V_{DDA} = 3.3$ V, $T_A = -40$ to 105 °C unless otherwise specified.

2. Guaranteed by design, not tested in production.

6.3.8 PLL characteristics

The parameters given in [Table 42](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 23: General operating conditions](#).

Table 42. PLL characteristics

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f_{PLL_IN}	PLL input clock ⁽¹⁾	1 ⁽²⁾	8.0	24 ⁽²⁾	MHz
	PLL input clock duty cycle	40 ⁽²⁾	-	60 ⁽²⁾	%
f_{PLL_OUT}	PLL multiplier output clock	16 ⁽²⁾	-	48	MHz
t_{LOCK}	PLL lock time	-	-	200 ⁽²⁾	μ s
Jitter _{PLL}	Cycle-to-cycle jitter	-	-	300 ⁽²⁾	ps

1. Take care to use the appropriate multiplier factors to obtain PLL input clock values compatible with the range defined by f_{PLL_OUT} .

2. Guaranteed by design, not tested in production.

6.3.9 Memory characteristics

Flash memory

The characteristics are given at $T_A = -40$ to 105 °C unless otherwise specified.

Table 43. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max ⁽¹⁾	Unit
t_{prog}	16-bit programming time	$T_A = -40$ to $+105$ °C	40	53.5	60	μ s
t_{ERASE}	Page (2 KB) erase time	$T_A = -40$ to $+105$ °C	20	-	40	ms
t_{ME}	Mass erase time	$T_A = -40$ to $+105$ °C	20	-	40	ms
I_{DD}	Supply current	Write mode	-	-	10	mA
		Erase mode	-	-	12	mA

1. Guaranteed by design, not tested in production.

Figure 25. ADC accuracy characteristics

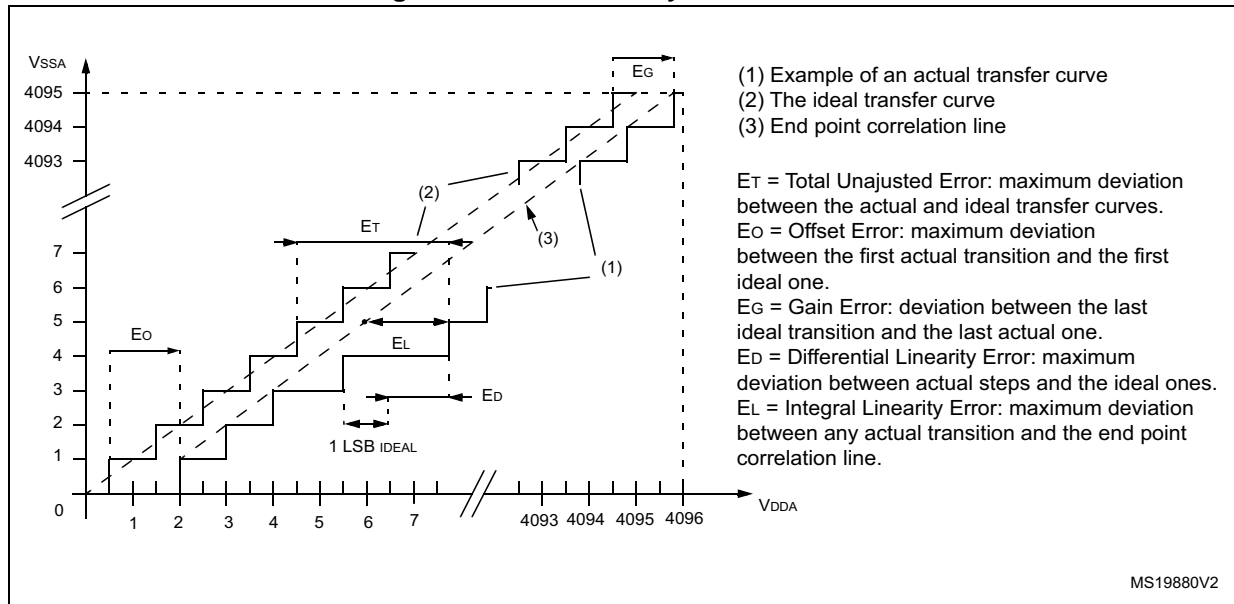
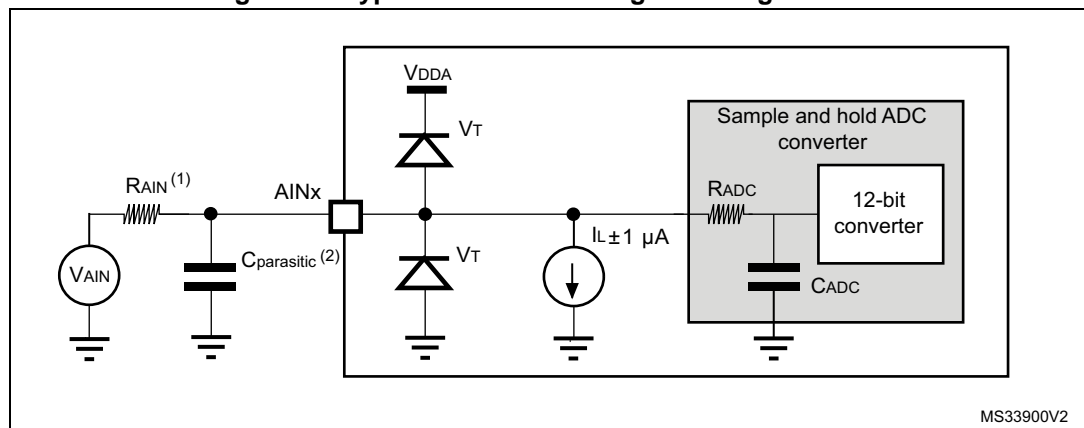


Figure 26. Typical connection diagram using the ADC



1. Refer to [Table 55: ADC characteristics](#) for the values of R_{AIN} , R_{ADC} and C_{ADC} .
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

General PCB design guidelines

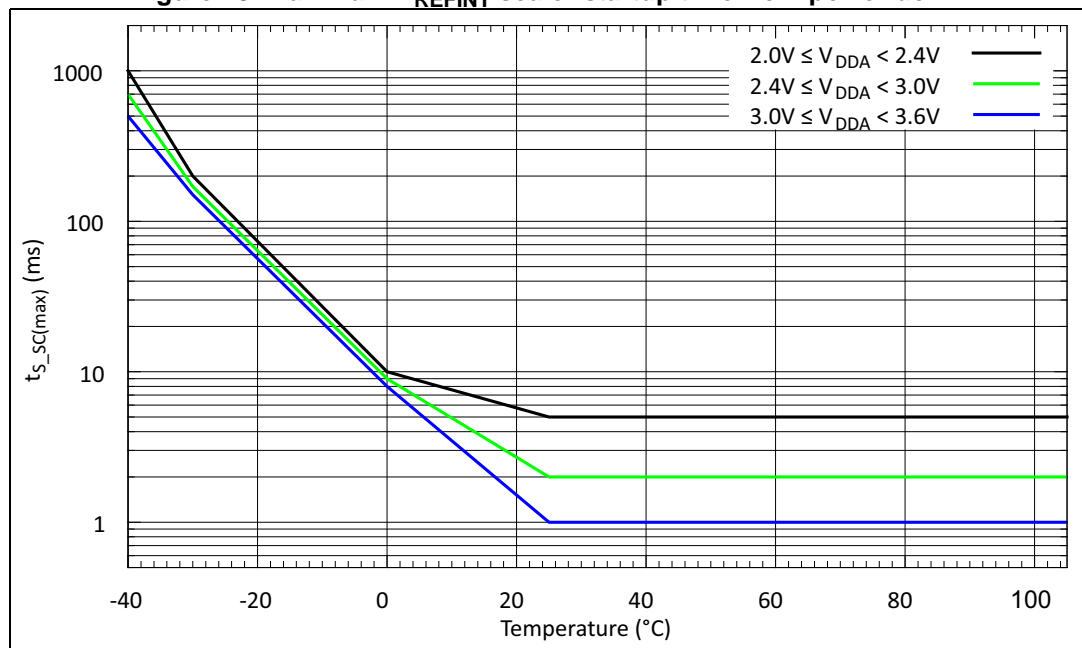
Power supply decoupling should be performed as shown in [Figure 12: Power supply scheme](#). The 10 nF capacitor should be ceramic (good quality) and it should be placed as close as possible to the chip.

Table 59. Comparator characteristics (continued)

Symbol	Parameter	Conditions	Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit
V_{hys}	Comparator hysteresis	No hysteresis (COMPxHYST[1:0]=00)	-	0	-	mV
		Low hysteresis (COMPxHYST[1:0]=01)	High speed mode	8	13	
			All other power modes		10	
		Medium hysteresis (COMPxHYST[1:0]=10)	High speed mode	15	26	
			All other power modes		19	
		High hysteresis (COMPxHYST[1:0]=11)	High speed mode	31	49	
			All other power modes		40	

1. Data based on characterization results, not tested in production.

2. For more details and conditions see [Figure 28: Maximum \$V_{\text{REFINT}}\$ scaler startup time from power down](#).

Figure 28. Maximum V_{REFINT} scaler startup time from power down

USB characteristics

The STM32F078CB/RB/VB USB interface is fully compliant with the USB specification version 2.0 and is USB-IF certified (for Full-speed device operation).

Table 68. USB electrical characteristics

Symbol	Parameter	Conditions	Min.	Typ	Max.	Unit
V_{DDIO2}	USB transceiver operating voltage	-	3.0 ⁽¹⁾	-	3.6	V
$t_{STARTUP}^{(2)}$	USB transceiver startup time	-	-	-	1.0	μs
R_{PUI}	Embedded USB_DP pull-up value during idle	-	1.1	1.26	1.5	kΩ
R_{PUR}	Embedded USB_DP pull-up value during reception	-	2.0	2.26	2.6	
$Z_{DRV}^{(2)}$	Output driver impedance ⁽³⁾	Driving high and low	28	40	44	Ω

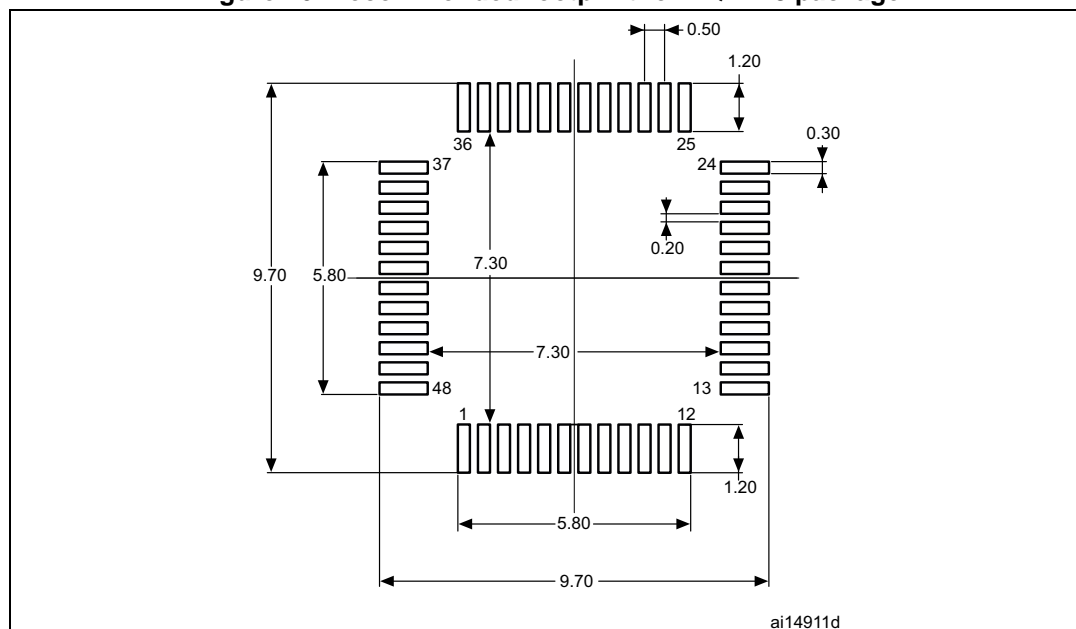
1. The STM32F078CB/RB/VB USB functionality is ensured down to 2.7 V but not the full USB electrical characteristics which are degraded in the 2.7-to-3.0 V voltage range.
2. Guaranteed by design, not tested in production.
3. No external termination series resistors are required on USB_DP (D+) and USB_DM (D-); the matching impedance is already included in the embedded driver.

Table 74. LQFP48 package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 46. Recommended footprint for LQFP48 package



1. Dimensions are expressed in millimeters.

As applications do not commonly use the STM32F078CB/RB/VB at maximum dissipation, it is useful to calculate the exact power consumption and junction temperature to determine which temperature range will be best suited to the application.

The following examples show how to calculate the temperature range needed for a given application.

Example 1: High-performance application

Assuming the following application conditions:

Maximum temperature $T_{Amax} = 82\text{ }^{\circ}\text{C}$ (measured according to JESD51-2), $I_{DDmax} = 50\text{ mA}$, $V_{DD} = 3.5\text{ V}$, maximum 20 I/Os used at the same time in output at low level with $I_{OL} = 8\text{ mA}$, $V_{OL} = 0.4\text{ V}$ and maximum 8 I/Os used at the same time in output at low level with $I_{OL} = 20\text{ mA}$, $V_{OL} = 1.3\text{ V}$

$$P_{INTmax} = 50\text{ mA} \times 3.5\text{ V} = 175\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} + 8 \times 20\text{ mA} \times 1.3\text{ V} = 272\text{ mW}$$

This gives: $P_{INTmax} = 175\text{ mW}$ and $P_{IOmax} = 272\text{ mW}$:

$$P_{Dmax} = 175 + 272 = 447\text{ mW}$$

Using the values obtained in [Table 76](#) T_{Jmax} is calculated as follows:

– For LQFP64, $45\text{ }^{\circ}\text{C/W}$

$$T_{Jmax} = 82\text{ }^{\circ}\text{C} + (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 82\text{ }^{\circ}\text{C} + 20.115\text{ }^{\circ}\text{C} = 102.115\text{ }^{\circ}\text{C}$$

This is within the range of the suffix 6 version parts ($-40 < T_J < 105\text{ }^{\circ}\text{C}$).

In this case, parts must be ordered at least with the temperature range suffix 6 (see [Section 8: Ordering information](#)).

Note: With this given P_{Dmax} we can find the T_{Amax} allowed for a given device temperature range (order code suffix 6 or 7).

$$\text{Suffix 6: } T_{Amax} = T_{Jmax} - (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 105 - 20.115 = 84.885\text{ }^{\circ}\text{C}$$

$$\text{Suffix 7: } T_{Amax} = T_{Jmax} - (45\text{ }^{\circ}\text{C/W} \times 447\text{ mW}) = 125 - 20.115 = 104.885\text{ }^{\circ}\text{C}$$

Example 2: High-temperature application

Using the same rules, it is possible to address applications that run at high temperatures with a low dissipation, as long as junction temperature T_J remains within the specified range.

Assuming the following application conditions:

Maximum temperature $T_{Amax} = 100\text{ }^{\circ}\text{C}$ (measured according to JESD51-2), $I_{DDmax} = 20\text{ mA}$, $V_{DD} = 3.5\text{ V}$, maximum 20 I/Os used at the same time in output at low level with $I_{OL} = 8\text{ mA}$, $V_{OL} = 0.4\text{ V}$

$$P_{INTmax} = 20\text{ mA} \times 3.5\text{ V} = 70\text{ mW}$$

$$P_{IOmax} = 20 \times 8\text{ mA} \times 0.4\text{ V} = 64\text{ mW}$$

This gives: $P_{INTmax} = 70\text{ mW}$ and $P_{IOmax} = 64\text{ mW}$:

$$P_{Dmax} = 70 + 64 = 134\text{ mW}$$

Thus: $P_{Dmax} = 134\text{ mW}$

Using the values obtained in [Table 76](#) T_{Jmax} is calculated as follows:

– For LQFP64, $45\text{ }^{\circ}\text{C/W}$

$$T_{Jmax} = 100\text{ }^{\circ}\text{C} + (45\text{ }^{\circ}\text{C/W} \times 134\text{ mW}) = 100\text{ }^{\circ}\text{C} + 6.03\text{ }^{\circ}\text{C} = 106.03\text{ }^{\circ}\text{C}$$

8 Ordering information

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Table 77. Ordering information scheme

Example:	STM32	F	078	R	B	T	6	x
Device family STM32 = ARM-based 32-bit microcontroller								
Product type F = General-purpose								
Sub-family 078 = STM32F078xx								
Pin count C = 48/49 pins R = 64 pins V = 100 pins								
User code memory size B = 128 Kbyte								
Package H = UFBGA T = LQFP U = UFQFPN Y = WLCSP								
Temperature range 6 = -40 to 85 °C 7 = -40 to 105 °C								
Options xxx = code ID of programmed parts (includes packing type) TR = tape and reel packing blank = tray packing								

9 Revision history

Table 78. Document revision history

Date	Revision	Changes
03-Apr-2014	1	Internal
28-May-2014	2	Initial release
17-Dec-2015	3	<p>Cover page:</p> <ul style="list-style-type: none"> – part numbers moved to title and table of part numbers removed – generic product name updated as STM32F078CB/RB/VB <p>Section 2: Description:</p> <ul style="list-style-type: none"> – <i>Figure 1: Block diagram</i> updated <p>Section 3: Functional overview:</p> <ul style="list-style-type: none"> – <i>Figure 2: Clock tree</i> updated – <i>Section 3.5.3: Low-power modes</i> - added information on peripherals configurable to operate with HSI <p>Section 4: Pinouts and pin descriptions:</p> <ul style="list-style-type: none"> – Package pinout figures updated (look and feel) – <i>Figure 8: WLCSP49 package pinout</i> - now presented in top view <p>Section 5: Memory mapping:</p> <ul style="list-style-type: none"> – <i>Figure 9: STM32F078CB/RB/VB memory map</i> updated <p>Section 6: Electrical characteristics:</p> <ul style="list-style-type: none"> – <i>Table 20: Voltage characteristics</i> and <i>Table 21: Current characteristics</i> updated – <i>Table 23: General operating conditions</i> - added footnote for V_{IN} of TTa I/O – <i>Table 25: Embedded internal reference voltage:</i> added t_{START} parameter and removed -40°-to-85° condition and associated note for V_{REFINT} – <i>Merger of tables 33 and 34 into Table 29: Typical current consumption, code executing from Flash memory, running from HSE 8 MHz crystal</i> – <i>Table 38: HSI oscillator characteristics</i> and <i>Figure 18: HSI oscillator accuracy characterization results for soldered parts</i> updated – <i>Table 39: HSI14 oscillator characteristics:</i> changed min values for ACC_{HSI14}, added test conditions – <i>Table 47: ESD absolute maximum ratings</i> updated – <i>Table 50: I/O static characteristics</i> - note removed – <i>Table 55: ADC characteristics</i> - updated some parameter values, test conditions and added footnotes ⁽³⁾ and ⁽⁴⁾ – <i>Table 58: DAC characteristics</i> - I_{DDA} max value (DAC DC current consumption) updated – <i>Table 59: Comparator characteristics</i> - min added for V_{DDA} – <i>Figure 28: Maximum V_{REFINT} scaler startup time from power down</i> added